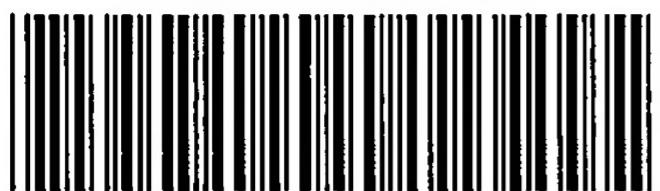


## **Search Notes**



**Application/Control No.**

**Applicant(s)/Patent under  
Reexamination**

10/655.919

BANICH ET AL.

Examiner

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## **Art Unit**

Tim Phan

3729

29/610 1

**SEARCHED**

## **INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

## **SEARCH NOTES (INCLUDING SEARCH STRATEGY)**